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Substitute for form 1449A/B/PTO				Complete if Known	
				Application Number	10/700,525
				Filing Date	November 5, 2003
				First Named Inventor	Masanari Furiki
				Art Unit	2878
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	H6808.0027/P027

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
BES	BA	JP 2002-124555	04/26/2002		

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BES	CA	KUROSAWA, ET AL., Establishment of the high throughput analysis method of the internal defect in a semiconductor device., pages 7-12 (2002), Japan.			

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Bernard Sow 08/13/04